

<b>Notice of References Cited</b>	Application/Control No. 10/684,737	Applicant(s)/Patent Under Reexamination KIM ET AL.	
	Examiner Rip A. Lee	Art Unit 1713	Page 1 of 1

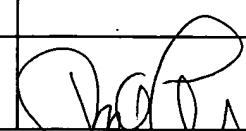
**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
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	M	US-			

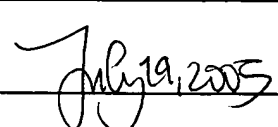
**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000-290431	10-2000	Japan	Yagi et al.	C08L 21/00
	O					
	P					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	JP 2000-290431 (abstract and translation in English)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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July 19, 2005